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Form PTO-1449 (Substitute) Information Disclosure Statement BY APPLICANT (Use several sheets if necessary)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Attorney Docket Number LAZE-01014US1	Application/Patent Number 10/684,661
	Applicant/Patent Owner Rust et al.		
	Filing/Issue Date 10/14/03	Group Art Unit 2827	

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UN	RE 36,603	03/07/00	Pohl et al.	365	151	08/20/96
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	5,166,919	11/24/92	Eigler et al.	369	126	07/11/91
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		5,861,754	01/19/99	Ueno et al.	324	660	07/15/97
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		2003/020725	11/06/03	Trivedi
		2003/0128494	07/10/03	Birecki et al.
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W		2004/0095868	05/20/04	Birecki et al.
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W	2005/0050258	03/03/05	Frommer et al.
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VN	2005/0055170	03/10/05	Gibson et al.
W	2005/0038950	02/17/05	Adelmann
	2005/0036428	02/17/05	Adelmann
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W	2006/0003493	01/05/06	Milligan et al.

PENDING U.S. PATENT APPLICATIONS

Examiner Initial	Application Number	Filing Date	First Named Inventor	Petition to Expunge? Yes No

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FOREIGN PATENT DOCUMENTS							
Examiner Initial		Document Number	Publication Date	Country	Class	Subclass	Translation Yes No

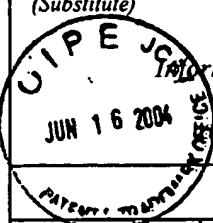
OTHER DOCUMENTS (Include author (if any), title, publisher and place of publication, date and pertinent pages)		

Examiner	/Viet Nguyen/ (07/02/2006)	Date Considered	7/02/06
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*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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				Applicant/Patent Owner Thomas F. Rust			
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U.S. PATENTS							
Examiner Initial		Patent Number	Issue Date	First Named Inventor	Class	Subclass	Filing Date
<i>W</i>	1	5,196,701	03/23/1993	Foster et al.	250	306	07/31/1991
	2	5,537,372	07/16/1996	Albrecht et al.	369	043	11/24/1993
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FOREIGN PATENT DOCUMENTS							
Examiner Initial		Document Number	Publication Date	Country	Class	Subclass	Translation Yes No
<i>W</i>	12	EP 0 788 149 A1	06/08/1997	EPO	H01L	21/3205	☒ ☐
<i>W</i>	13	WO 02/37488 A1	05/10/2002	PCT	G11B	9/00	☒ ☐
<i>W</i>	14	WO 97/05610	02/13/1997	PCT	G11B	9/00	☒ ☐
OTHER DOCUMENTS (Include author (if any), title, publisher and place of publication, date and pertinent pages)							
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Examiner <u>V. Nguyen</u> Date Considered <u>11/12/05</u>		
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